- Meets or Exceeds the Requirements of ANSI EIA/TIA-422-B and RS-485
- High-Speed Advanced Low-Power Schottky Circuitry
- Designed for up to 20-Mbps Operation in Both Serial and Parallel Applications
- Designed for Multipoint Transmission on Long Bus Lines in Noisy Environments
- Low Supply Current Requirements 55 mA Max
- Wide Positive and Negative Input/Output Bus Voltage Ranges
- Driver Output Capacity . . . ±60 mA
- Thermal-Shutdown Protection
- Driver Positive- and Negative-Current Limiting
- Functionally Interchangeable With SN75174

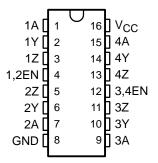
description

The SN65ALS174A and SN75ALS174A are quadruple line drivers with 3-state differential outputs. They are designed to meet the requirements of ANSI Standards EIA/TIA-422-B and RS-485. These devices are optimized for balanced multipoint bus transmission at rates of up to 20 Mbps. Each driver features wide positive and negative common-mode output voltage ranges that make them suitable for party-line applications in noisy environments.

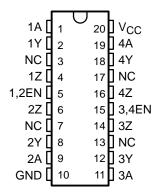
The SN65ALS174A and SN75ALS174A provide positive- and negative-current limiting and thermal shutdown for protection from line fault conditions on the transmission bus line. Shutdown occurs at a junction temperature of approximately 150°C.

The SN65ALS174A is characterized for operation from -40°C to 85°C and the SN75ALS174A is characterized for operation from 0°C to 70°C .

SN75ALS174A . . . N PACKAGE (TOP VIEW)



SN65ALS174A, SN75ALS174A . . . DW PACKAGE (TOP VIEW)



NC-No internal connection

FUNCTION TABLE (each driver)

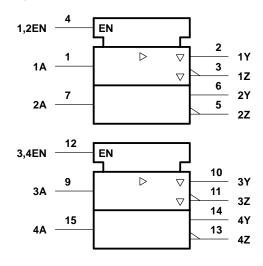
INPUT	ENABLES	OUTPUTS			
Α	LIVABLES	Y	Z		
Н	Н	Н	L		
L	Н	L	Н		
X	L	Z	Z		

H = high level, L = low level, X = irrelevant, Z = high impedance (off)

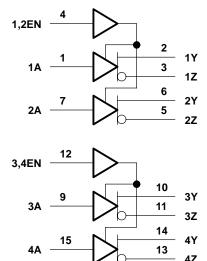


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logic symbol†

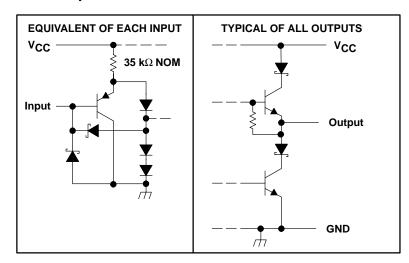


logic diagram (positive logic)



Pin numbers shown are for the N package.

schematics of inputs and outputs



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN65ALS174A, SN75ALS174A QUADRUPLE DIFFERENTIAL LINE DRIVERS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC} (see Note 1)	
Input voltage, V _I	
Output voltage range, VO	–9 V to 14 V
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T _A : SN65ALS174A	–40°C to 85°C
SN75ALS174A	0°C to 70°C
Storage temperature range, T _{stq}	–65°C to 150°C
Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds	260°C

NOTE 1: All voltage values are with respect to network GND.

DISSIPATION RATING TABLE

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING
DW	1125 mW	9.0 mW/°C	720 mW	585 mW
N	1150 mW	9.2 mW/°C	736 mW	598 mW

recommended operating conditions

		MIN	NOM	MAX	UNIT	
Supply voltage, V _{CC}			5	5.25	V	
High-level input voltage, V _{IH}		2			V	
Low-level input voltage, V _{IL}	Low-level input voltage, V _{IL}			0.8	V	
Common-mode output voltage, V _{OC}				12 -7	V	
High-level output current, IOH				-60	mA	
Low-level output current, IOL				60	mA	
Operating free-air temperature, T _A	SN65ALS174A	-40		85	³⁵ ∘C	
Operating nee-an temperature, 14	SN75ALS174A	0		70	C	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

SN65ALS174A, SN75ALS174A QUADRUPLE DIFFERENTIAL LINE DRIVERS

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electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CO	NDITIONS	MIN	TYP [†]	MAX	UNIT
VIK	Input clamp voltage	I _I = –18 mA				-1.5	V
۷o	Output voltage	IO = 0	IO = 0			6	V
V _{OD1}	Differential output voltage	I _O = 0		1.5		6	V
V _{OD2}	Differential output voltage	R _L = 100 Ω	See Figure 1	1/2 V _{OD1} or 2 [‡]			V
		$R_L = 54 \Omega$		1.5	2.5	5	
VOD3	Differential output voltage	See Note 2		1.5		5	V
Δ V _{OD}	Change in magnitude of differential output voltage§					±0.2	V
Voc	Common-mode output voltage¶	R_L = 54 Ω or 100 Ω ,	See Figure 1			3 -1	V
Δ VOC	Change in magnitude of common-mode output voltage§					±0.2	V
IO	Output current with power off	$V_{CC} = 0$,	$V_0 = -7 \text{ V to } 12 \text{ V}$			±100	μΑ
loz	High-impedance-state output current	$V_0 = -7 \text{ V to } 12 \text{ V}$				±100	μА
lн	High-level input current	V _I = 2.7 V				20	μΑ
I _{IL}	Low-level input current	V _I = 0.4 V				-100	μΑ
los	Short-circuit output current	$V_0 = -7 \text{ V to } 12 \text{ V}$				±250	mA
laa	Supply current (all drivers)	No load	Outputs enabled		36	55	mA
Icc		No load	Outputs disabled		16	30	IIIA

[†] All typical values are at $V_{CC} = 5 \text{ V}$ and $T_A = 25^{\circ}\text{C}$.

NOTE 2: See EIA Standard RS-485, Figure 3-5, Test Termination Measurement 2.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50 \text{ pF}$

PARAMETER		TEST CONDITIONS		MIN	түр†	MAX	UNIT
td(OD)	Differential output delay time	$R_L = 54 \Omega$,	See Figure 2	9	15	22	ns
^t PZH	Output enable time to high level	$R_L = 110 \Omega$,	See Figure 3	30	45	70	ns
tPZL	Output enable time to low level	$R_L = 110 \Omega$,	See Figure 4	25	40	65	ns
t _{PHZ}	Output disable time from high level	$R_L = 110 \Omega$,	See Figure 3	10	20	35	ns
t _{PLZ}	Output disable time from low level	$R_L = 110 \Omega$,	See Figure 4	10	30	45	ns

[†] All typical values are at $V_{CC} = 5 \text{ V}$ and $T_A = 25^{\circ}\text{C}$.

 $[\]ddagger$ The minimum V_{OD2} with a 100- Ω load is either 1/2 V_{OD1} or 2 V, whichever is greater.

[§] Δ | V_{OD} | and Δ | V_{OC} | are the changes in magnitude of V_{OD} and V_{OC} , respectively, that occur when the input is changed from a high level to a low level.

[¶] In ANSI Standard EIA/TIA-422-B, V_{OC}, which is the average of the two output voltages with respect to ground, is called output offset voltage, V_{OS}.

PARAMETER MEASUREMENT INFORMATION

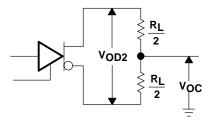
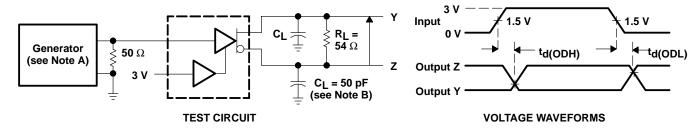
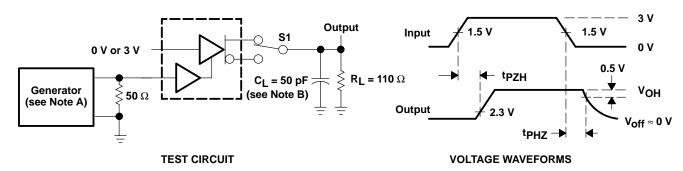


Figure 1. Differential and Common-Mode Output Voltages



- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz, Z_O = 50 Ω , duty cycle = 50%, $t_f \le 5$ ns.
 - B. C_L includes probe and stray capacitance.

Figure 2. Differential-Output Test Circuit and Delay and Transition Times Voltage Waveforms

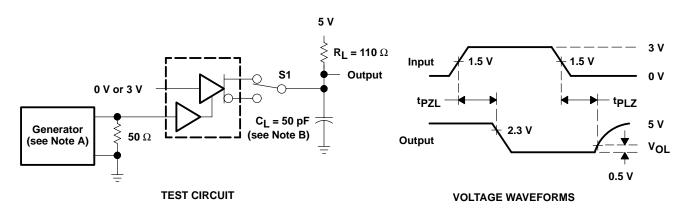


- NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz, $Z_O = 50 \Omega$, duty cycle = 50%, $t_f \le 5$ ns.
 - B. C_L includes probe and stray capacitance.

Figure 3. Test Circuit and Voltage Waveforms, tpZH and tpHZ

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR = 1 MHz, $Z_O = 50 \Omega$, duty cycle = 50%, $t_f \le 5$ ns. $t_C \le 5$ ns.

B. C_L includes probe and stray capacitance.

Figure 4. Test Circuit and Voltage Waveforms, tpZL and tpLZ

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